Application/Control No.	Applicant(s)/Patent under Reexamination
10/763,981	VIGH, GYULA
Examiner	Art Unit
Surekha Vathyam	1753

SEARCHED					
Class	Subclass	Date	Examiner		
204	548, 644	8/29/2007	sv		
204	450-470	8/29/2007	SV		
204	600-621	8/29/2007	sv		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
:					

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
see attached EAST search history	8/29/2007	sv
Inventor nam esearch on EAST and Google Scholar	8/29/2007	sv
Searched Google Scholar keywords IEF auxiliary pH bias	8/29/2007	sv
Consulted Alex Noguerola for search	8/29/2007	sv